

NLG2132 TRANSIMPEDANCE AMPLIFIER(BARE DIE)

This NLG2132 is a GaAs MESFET IC Chip that performs signal amplification over the wide frequency range extending from DC to 7.7 GHz. This IC Chip is applicable to 10 Gb/s optical fiber communication systems.

The NLG2132 is fabricated using the 0.15 μm gate length A-SAINT(Advanced Self - Aligned Implantation for N+ layer Technology) process.



FEATURES

- Ultra-Wideband : DC ~7.7 GHz
- High Data Rates : 10 Gb/s NRZ
- High Transimpedance Gain : 52 dB Ω (Typ.)
- Low Noise : 12 pA/ $\sqrt{\text{Hz}}$ at 5 GHz (Typ.)

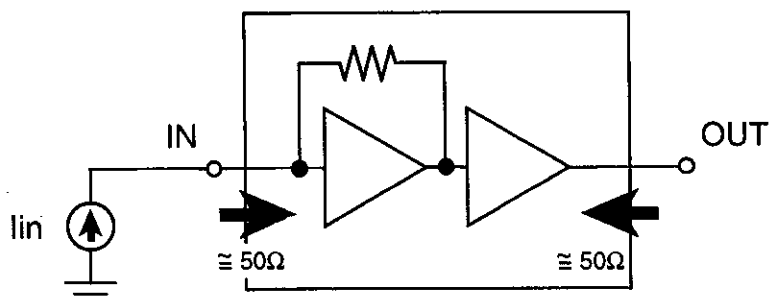
APPLICATIONS

- O/E Transfer module
- Equalizing amplification for optical communication
- Low noise amplification for radio communication

FUNCTION TABLE

IN	OUT
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	L

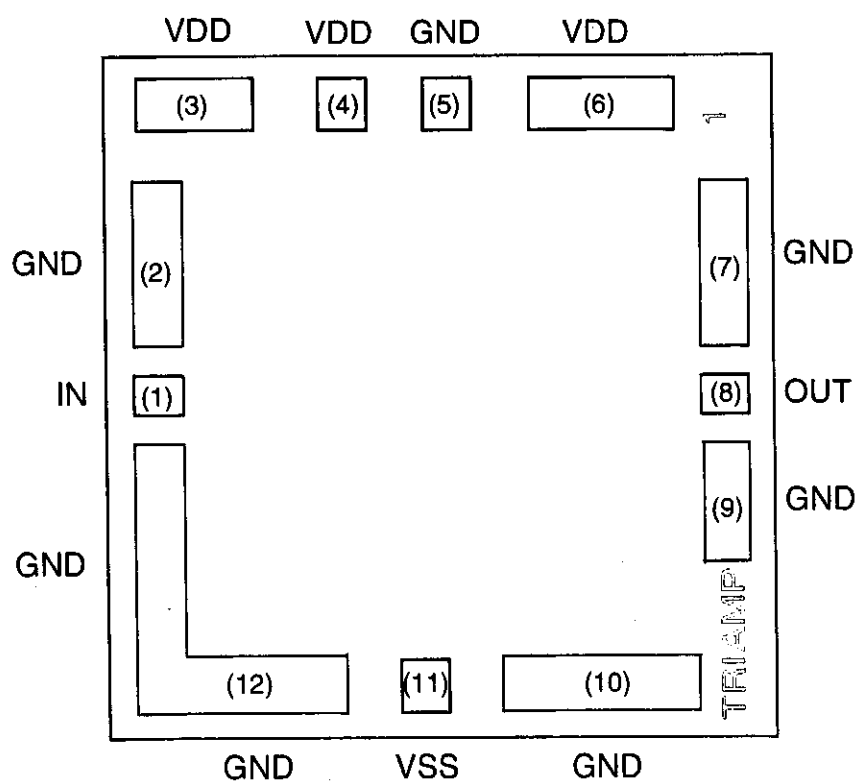
FUNCTION DIAGRAM



PAD ASSIGNMENT

PAD No.	SYMBOL	FUNCTION
1	IN	Input
2	GND	Ground (0.0 V)
3	VDD	Power Supply (+ 9.0 V)
4	VDD	Power Supply (+ 9.0 V)
5	GND	Ground (0.0 V)
6	VDD	Power Supply (+ 9.0 V)
7	GND	Ground (0.0 V)
8	OUT	Output
9	GND	Ground (0.0 V)
10	GND	Ground (0.0 V)
11	VSS	Power Supply (-3.5 V)
12	GND	Ground (0.0 V)

PAD LOCATIONS



ABSOLUTE MAXIMUM RATINGS

(Ta= 25 °C)

SYMBOL	PARAMETER	RATING	UNITS
VDD	Power Supply	11	V
VSS	Power Supply	-5	V
IIN	Current Applied to Input	6.5	mApp
Tstor	Storage Temperature	-60 ~ +150	°C
TCB	Chip Bottom temperature under Bias	-60 ~ +125	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNITS
VDD	Power Supply	8.55	9.0	9.45	V
VSS	Power Supply	-3.75	-3.5	-3.4	V
IIN	Current Applied to Input			2	mApp

ELECTRICAL CHARACTERISTICS

(VDD= 8.55 ~ 9.45 V, VSS= -3.75 ~ -3.40 V, Input and Output terminal : AC coupling, Zo=50 Ω)

SYMBOL	PARAMETER	CONDITION	TCB=0°C			TCB=25°C			TCB=90°C			UNITS
			MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
IDD	Supply Current			77	120		78	120		79	120	mA
ISS	Supply Current			25	38		25	38		25	38	mA
f-3dB	3dB Bandwidth *1	C=0.2pF *2 L=0.5nH *3	7.7G	7.9G		7.5G	7.7G		6.8G	7.0G		Hz
Zt	Transimpedance Gain	f=200MHz C=0.2pF *2 L=0.5nH *3	50	52	54	50	52	54	50	51	53	dB Ω
ΔZtp	Frequency Response *4 Gain Peak	f=100MHz~10GHz C=0.2pF *2 L=0.5nH *3		1.3	2.3		1.0	2.0		0.6	1.6	dB
ΔZtd	Frequency Response *4 Gain Dip	f=100MHz~5GHz C=0.2pF *2 L=0.5nH *3		0.6	1.2		0.6	1.2		0.8	1.4	dB
S22	Output Return Loss *5	f=100MHz~10GHz	5.0	6.5		5.0	7.5		5.0	8.0		dB
In	Input Current Noise Spectral Density	f=5GHz C=0.2pF *2		12	18		12	18		14	20	pA/√Hz
Vin	Input DC Offset Voltage		-0.39	0.01	0.41	-0.40	0.00	0.40	-0.41	-0.01	0.39	V

*1 The frequency at which gain has been reduced by 3dB from the gain Zt

*2 Photodiode capacitance

*3 The inductance of bonding wire between photodiode and transimpedance amplifier

*4 Referenced from 100MHz

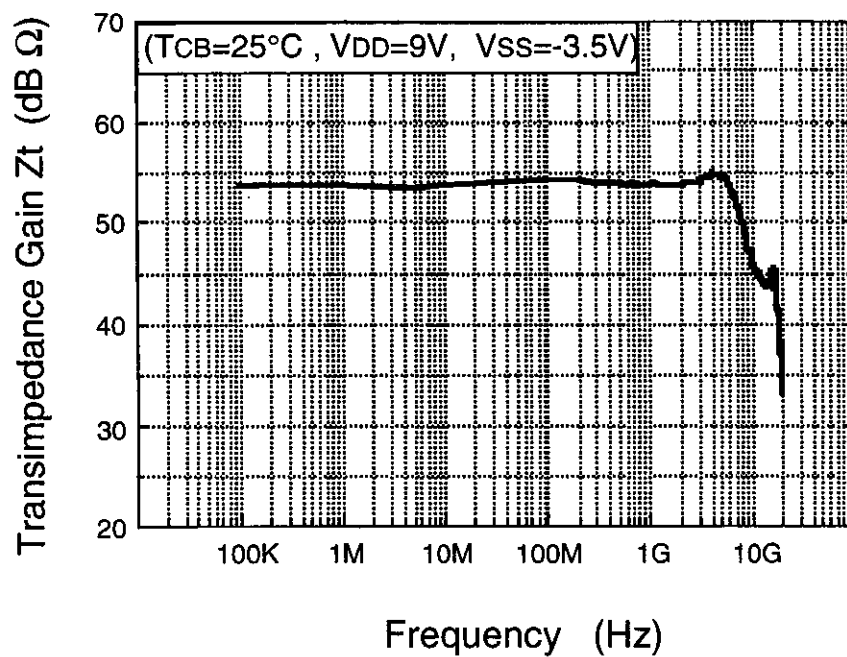
*5 Minimum Value at frequency range of 100MHz ~ 10GHz

1. SMALL SIGNAL INPUT CHARACTERISTICS

(1-1) SAMPLE TRANSIMPEDANCE GAIN

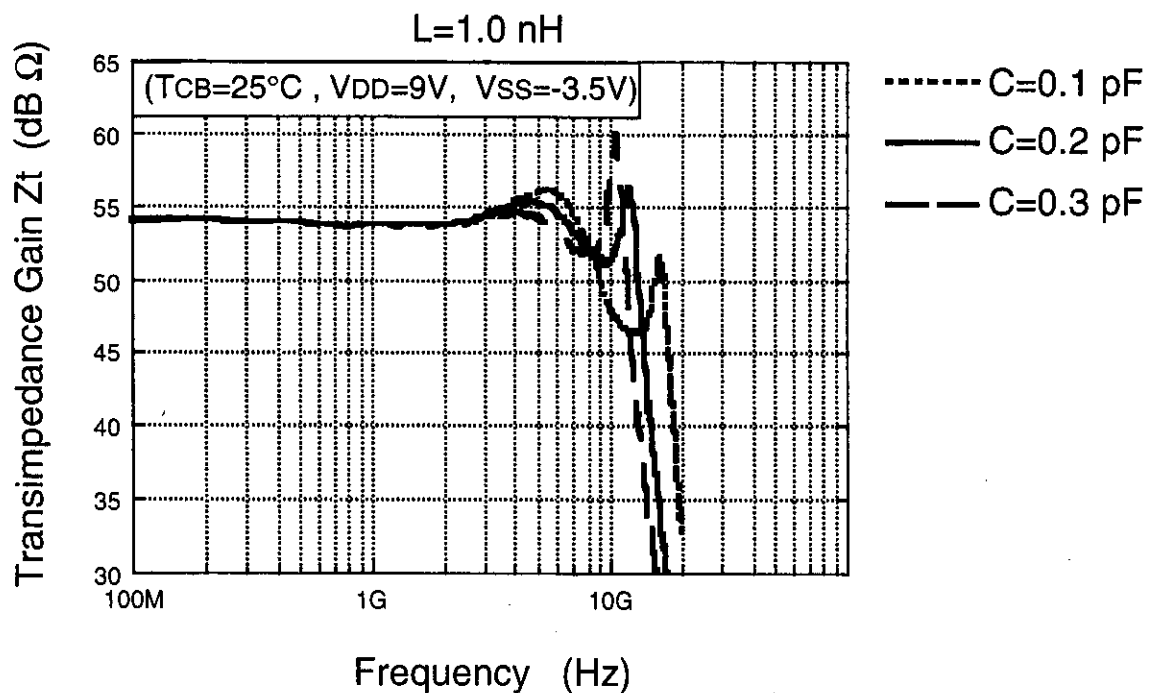
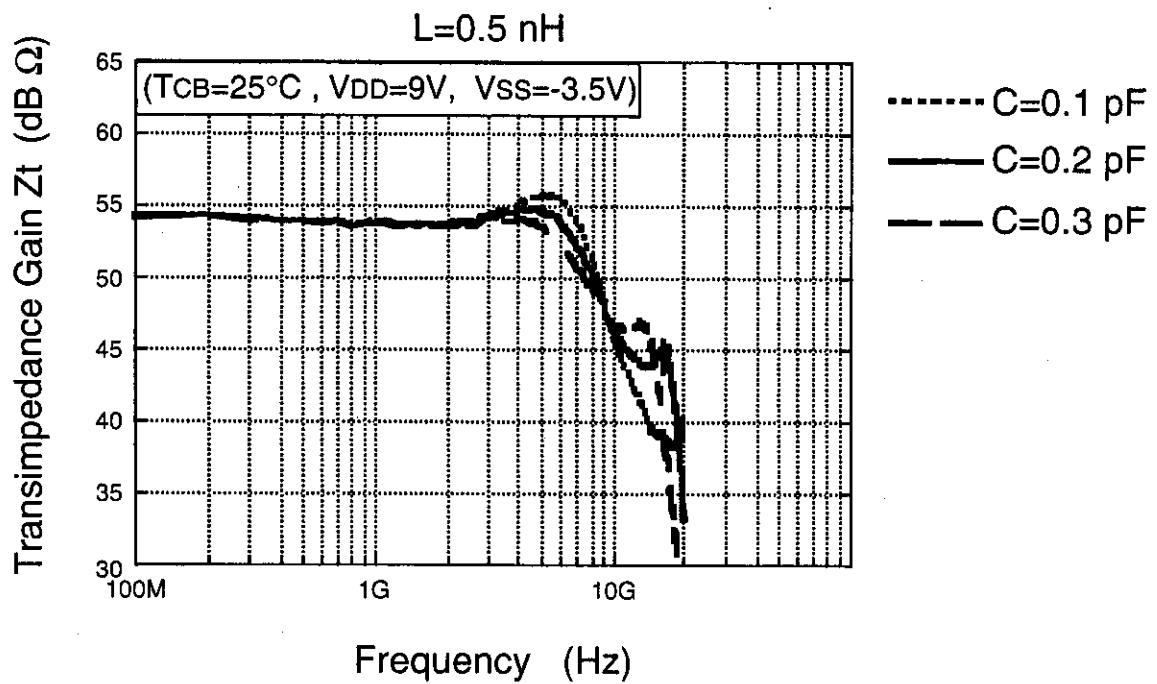
Photodiode capacitance : $C=0.2$ pF

The inductance of bonding wire between photodiode and transimpedance amplifier : $L=0.5$ nH

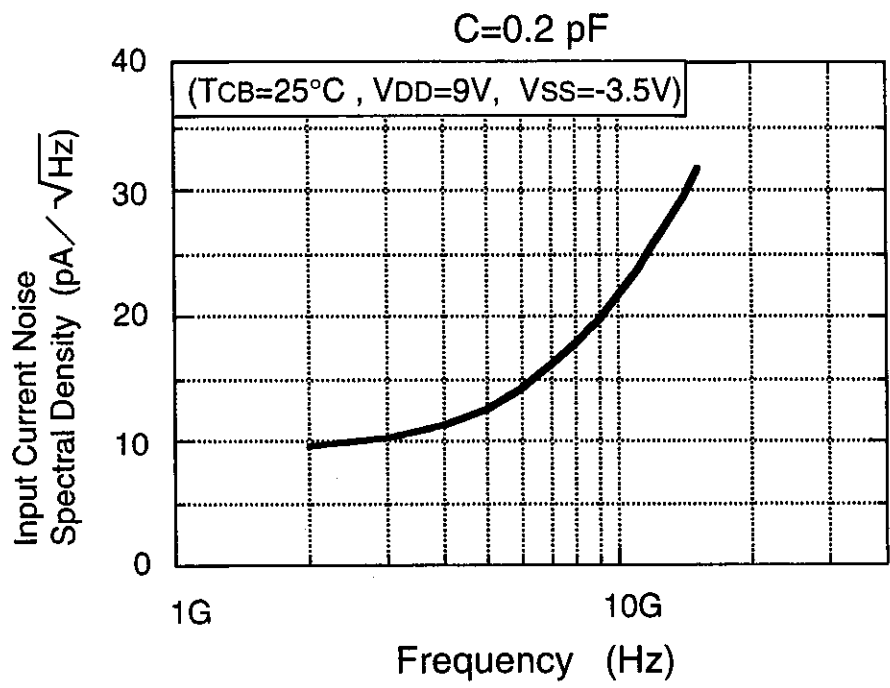


(1-2) SAMPLE TRANSIMPEDANCE GAIN

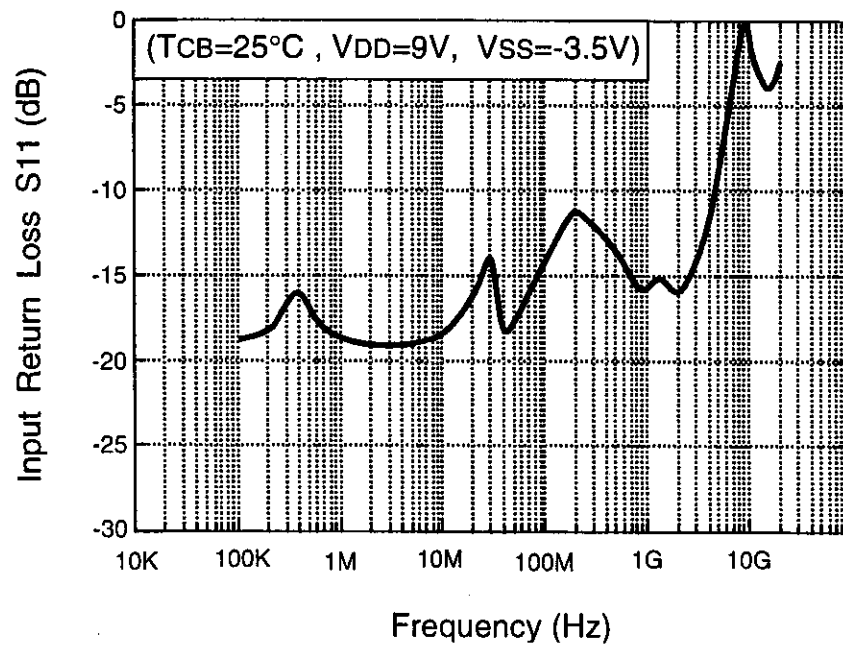
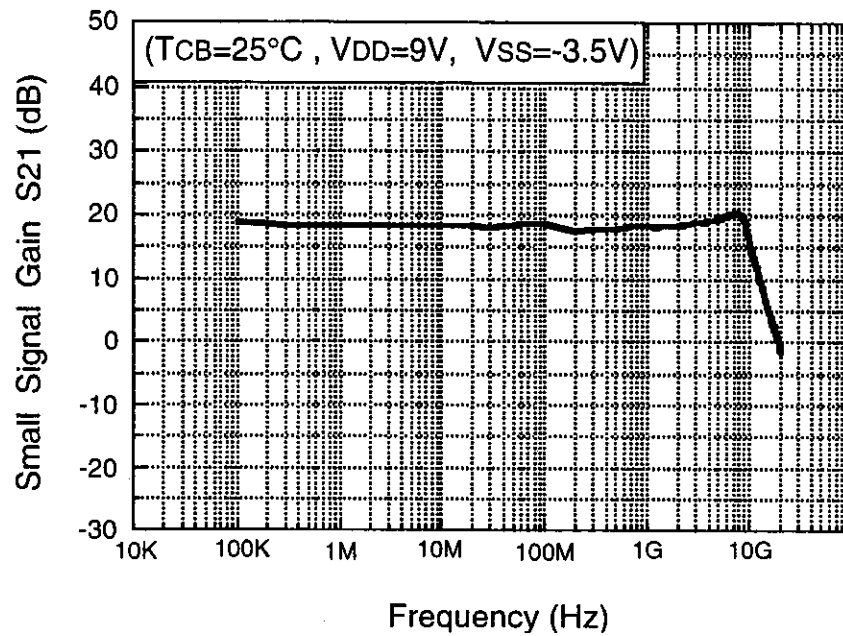
(Frequency dependence for various photodiode capacitance)

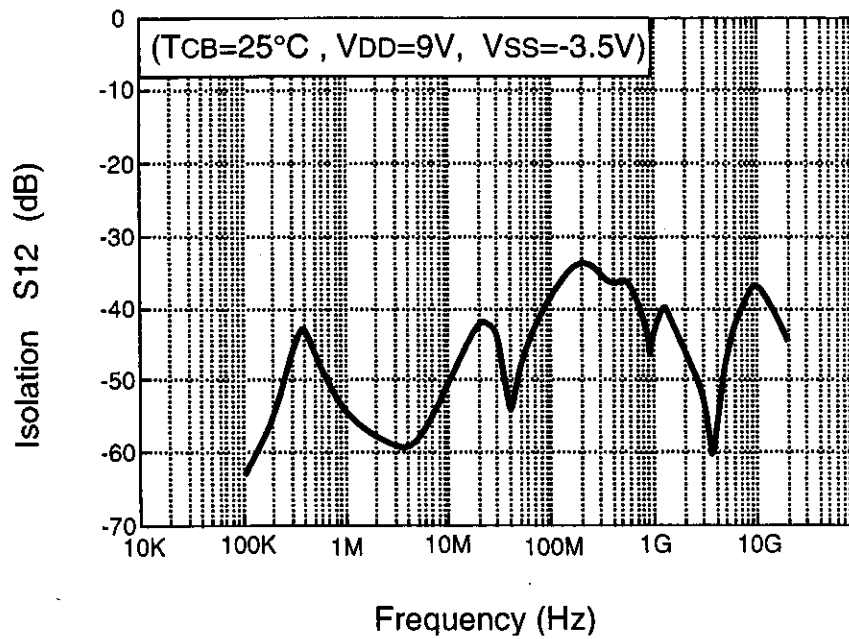
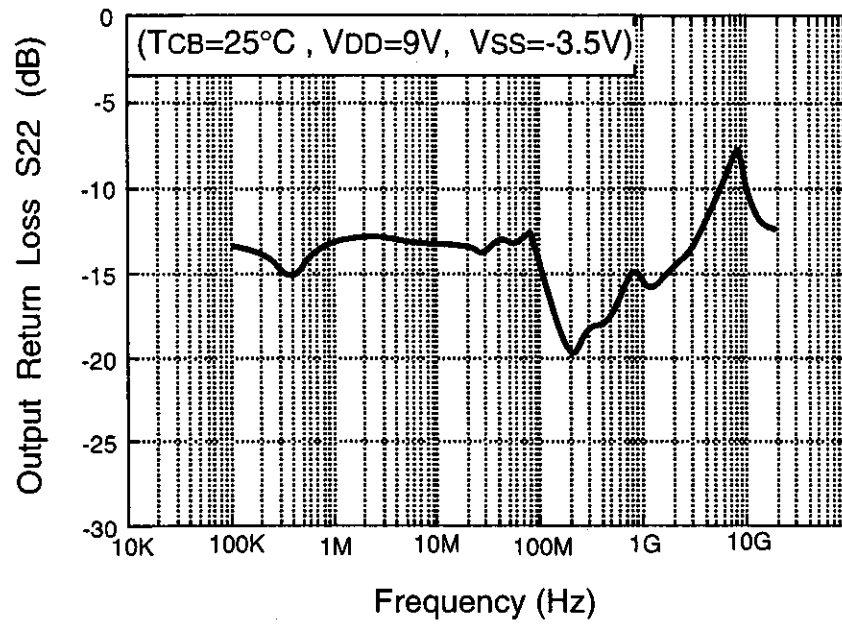


(1-3) SAMPLE INPUT CURRENT
NOISE SPECTRAL DENSITY

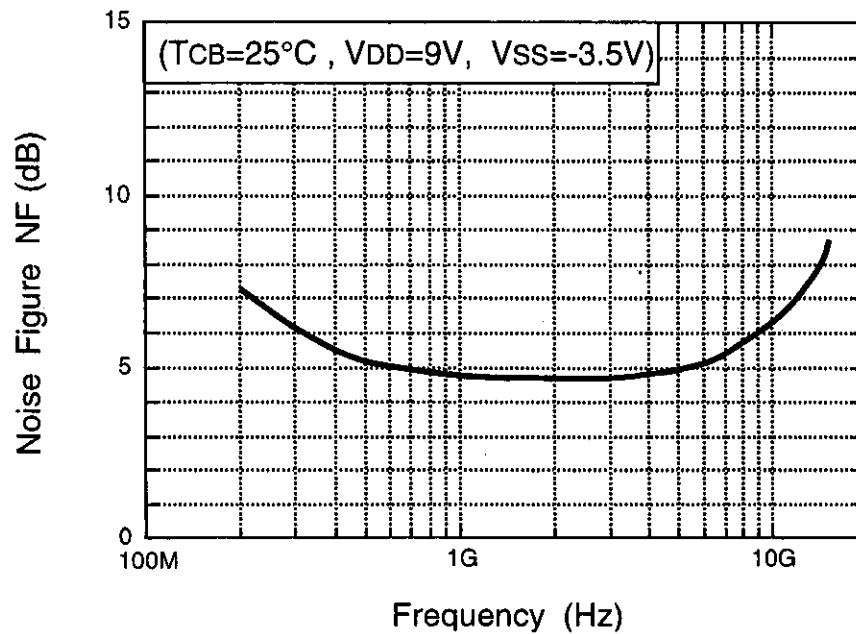


(1-4) SAMPLE S-PARAMETERS

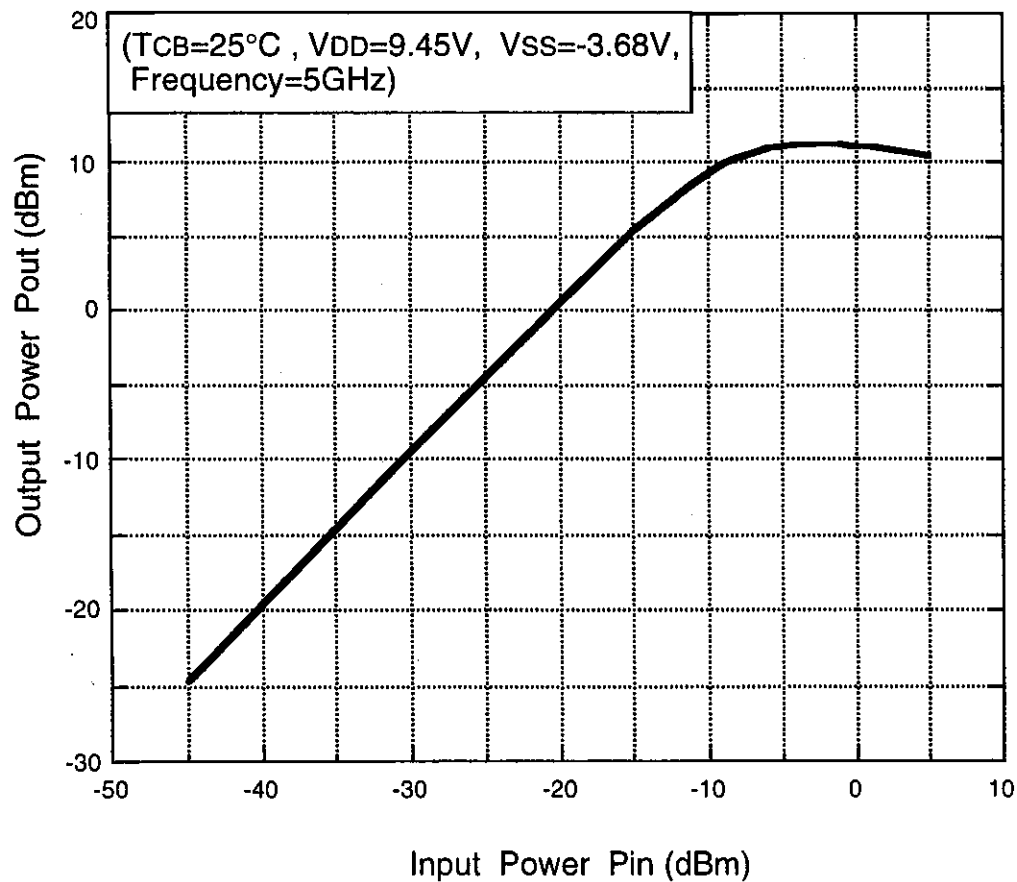




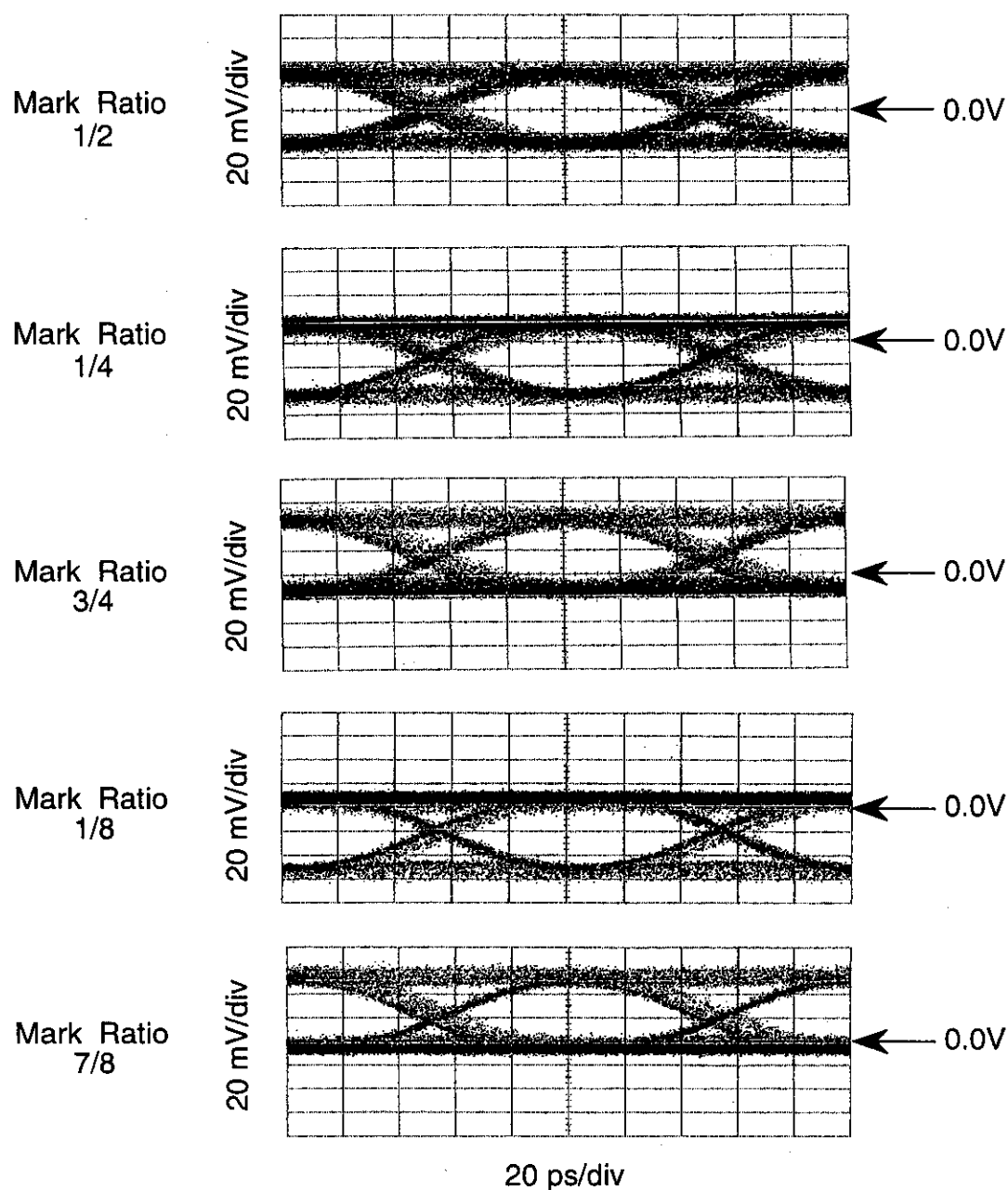
(1-5) SAMPLE NOISE FIGURE



(1-6) SAMPLE INPUT/OUTPUT CHARACTERISTICS



2. OUTPUT WAVEFORMS : PSEUDO-RANDOM INPUT SIGNAL RESPONSE



Measurement Conditions

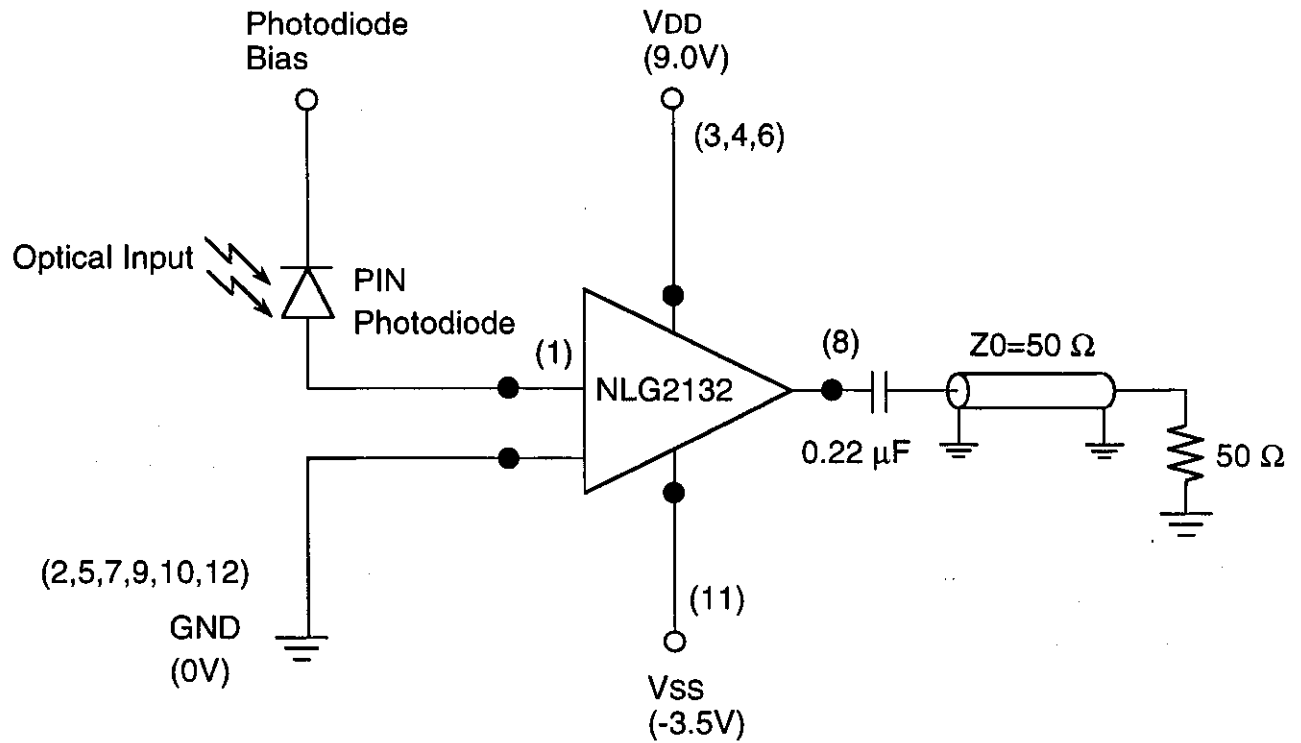
VDD=9.0V, VSS=-3.5V. DC blocking capacitance C=0.22 μ F.

Input data a 10Gb/s pseudo-random pattern having a word length of $2^{23}-1$ bits, where input signal amplitude is 0.009Vpp.

Error-free operation (an error rate less than $1E-13$) confirmed.

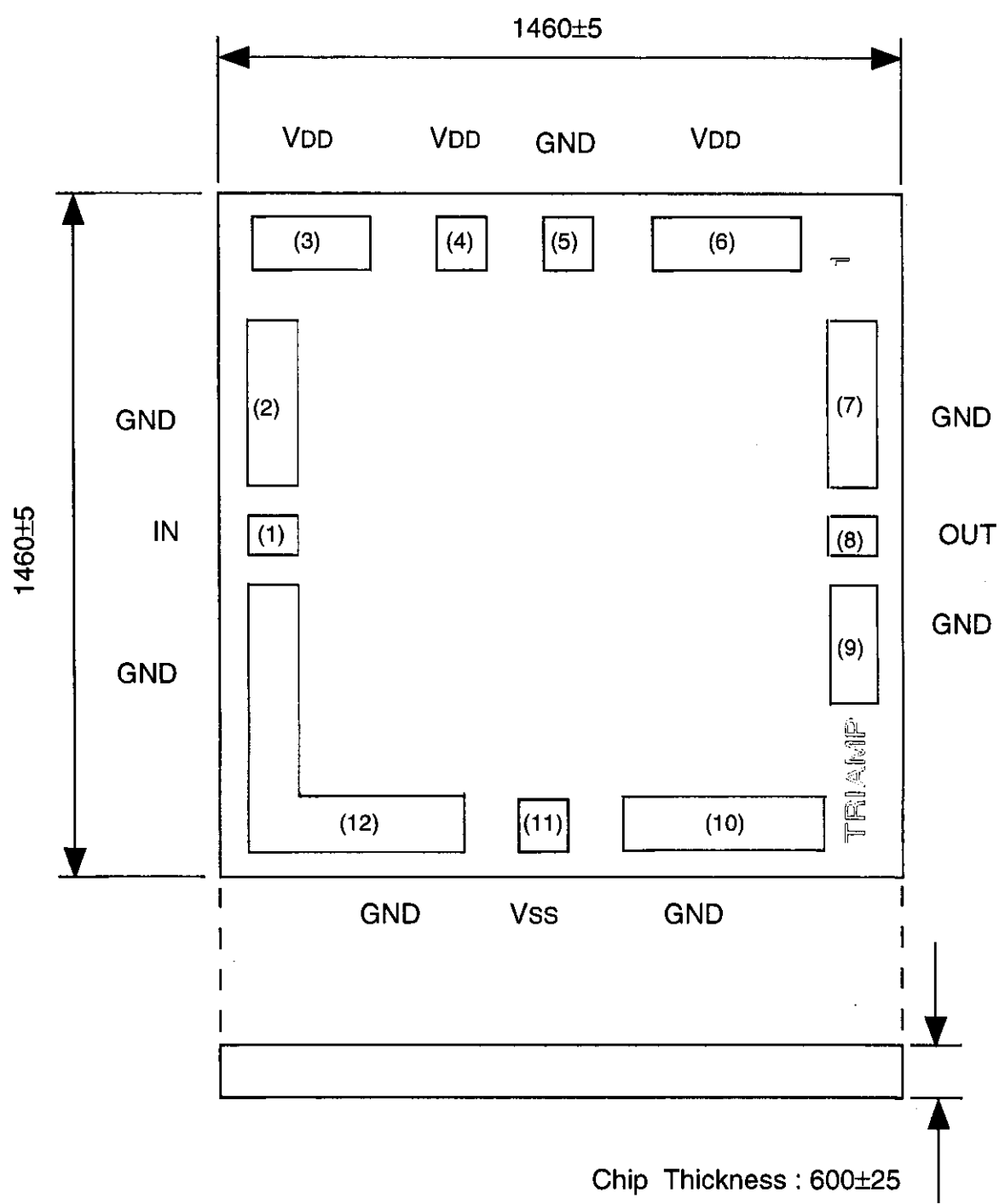
SAMPLE IMPLEMENTATION

Notes : Numbers represent pad numbers



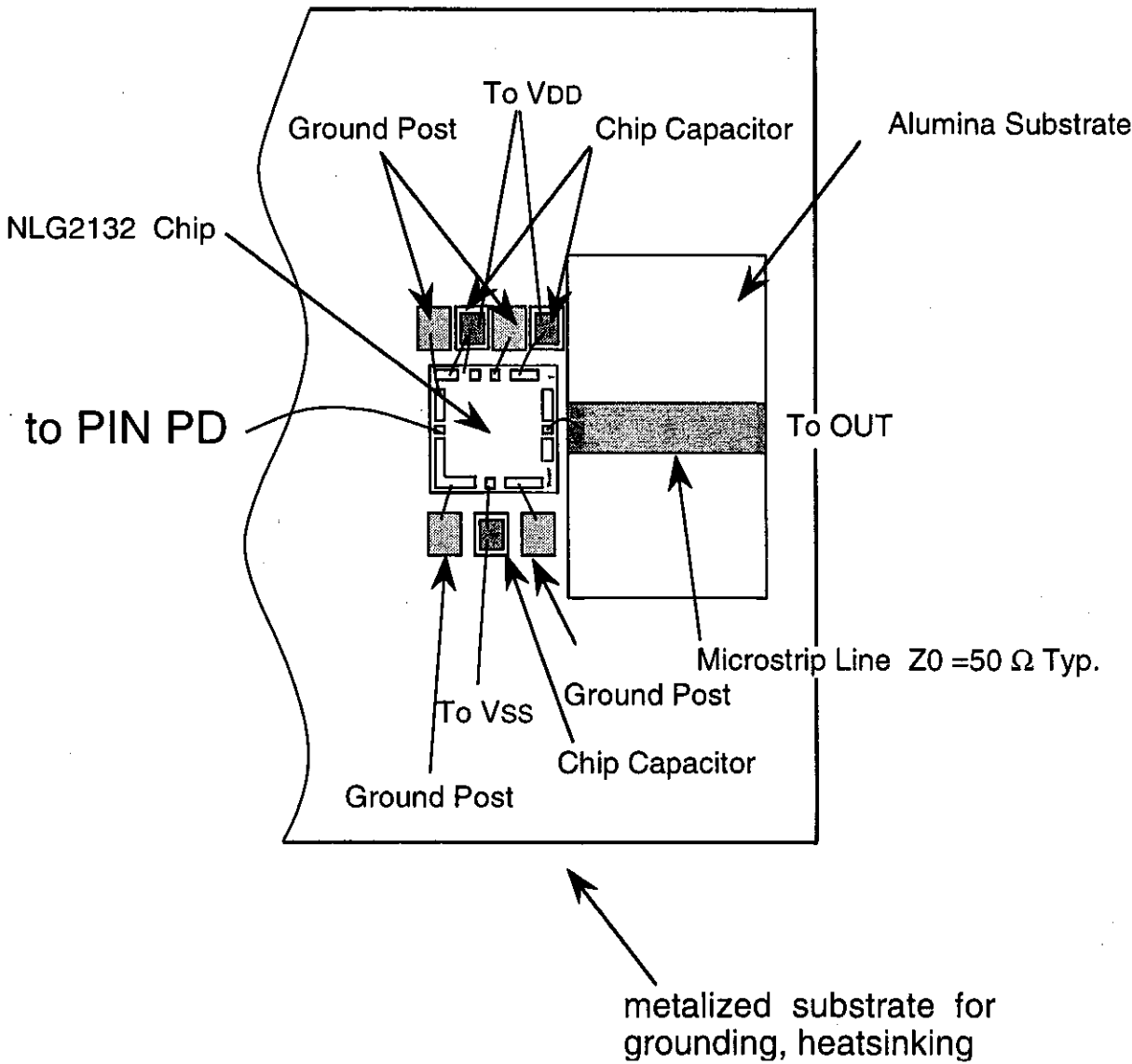
CHIP STRUCTURE

Unit : μm



MOUNTING EXAMPLE

Top View



OPERATING AND HANDLING INSTRUCTIONS

Since the NLG2132 is fabricated with GaAs MESFET's (Metal Semiconductor Field Effect Transistors), users are recommended to follow the instructions below to prevent damage to the chip from electro-statics discharge.

(1) Handling Precautions

- 1) IC chips are very fragile and handling should be minimized.
- 2) Use a conductive working desk connected to the ground (or, a conductive table top connected to the ground).
- 3) Require all handling personnel to wear a conductive bracelet or wrist-strap connected to the ground through a 1 M-ohm resistor.
- 4) Ground all test equipment.

(2) Storing Precautions

IC chips should be stored in dry-nitrogen, vacuum, or moisture-free sealed environment.

(3) Power supply sequence

The following power supply sequence is recommended.

- 1) Set supply voltages VDD, VSS and GND to 0 V.
- 2) Apply VSS.
- 3) Apply VDD.

RF signal is recommended to be applied while power supplying.

Caution

1. In order to improve products and technology, specifications are subject to change without notice.
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